

STANDARD PROBE STATION

**SPS 4/6**



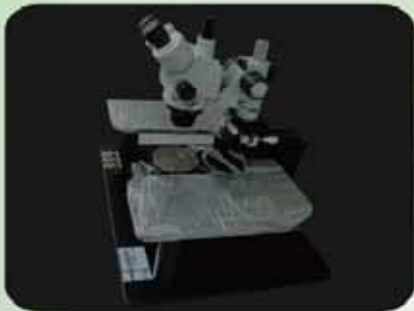
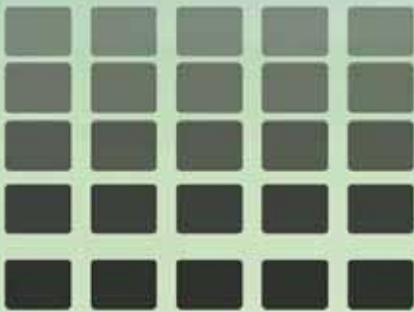
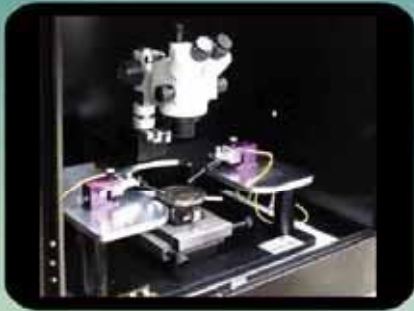
**MICROTEST**

Equipment & Consumables for the  
semiconductors and hybrids



**Swin**

## SPS Series Probe Station (APS 4/6)



### Features

- Fine Movement Knob Adjustment for Chuck X-Y
- RF Probing Field Upgradeable
- Backlash-Free Movement

### Specifications

- Vacuum chuck : 4" / 6" stainless steel
- Chuck stage travel : 100 / 150mm
- Chuck theta : 0 ~ 30 degree
- Chuck up / down : 5mm
- Microscope stage travel : 15mm x 15mm
- Sample size: 5x5mm ~ 4" / 6"
- Chuck flatness: 10um

### Option

- Gold plated vacuum chuck
- Thermal systems
- Chuck vacuum pattern
- RF probes/cables
- Active probes
- Low current/capacitance probes
- High voltage probes
- CCD/Digital camera with USB connection
- Vibration free table
- Shielding box
- Instrument case with caster

### Dimensions

- Dimension (W/D/H) :
  - SPS 4 : 580mm x 460mm x 245mm
  - SPS 6 : 580mm x 460mm x 400mm
- Weight : 41.5 kg (SPS 4) , 45.5 kg (SPS 6)

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